Characteristics	Symbols	MIL-STD-883 Test Method	Test Conditions Note 1	Limits		Units
				Min	Max	
Propagation Delay Low to High, 1A to 1B	t_{PLH}	3003	V_{IN}(Under Test)=Pulse Generator V_{IN} (Remaining Inputs)=Truth Table V_{IL}=0V, V_{IH}=5V, R_L=200kΩ V_{DD}=5V, V_{SS}=0V Note 8	-	40	ns
Propagation Delay High to Low, 1A to 1B	t_{PHL}	3003	V_{IN}(Under Test)=Pulse Generator V_{IN} (Remaining Inputs)=Truth Table V_{IL}=0V, V_{IH}=5V, R_L=200kΩ V_{DD}=5V, V_{SS}=0V Note 8	-	40	ns
Output Enable Time High Impedance to High Output, 1C to 1B	t_{PZH}	3003	V_{IN}(Under Test)=Pulse Generator V_{IN} (Remaining Inputs)=Truth Table V_{IL}=0V, V_{IH}=5V, V_{IN}(1A)=5V, R_L=1kΩ V_{DD}=5V, V_{SS}=0V Note 8	-	70	ns

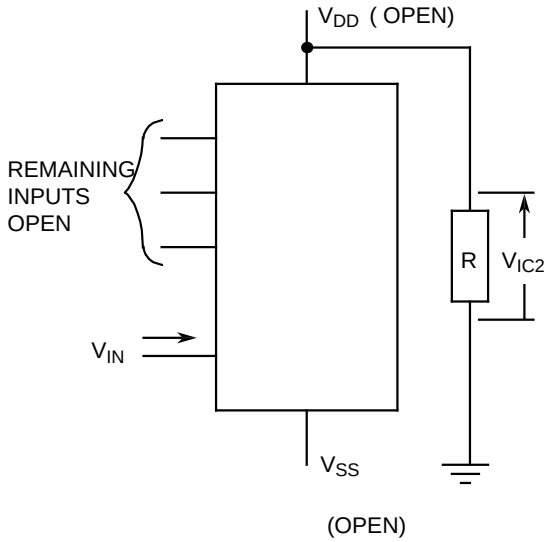
2.3.2 High and Low Temperatures Electrical Measurements

The measurements shall be performed at T_{amb}=+125 (+0 -5) ^{o}C and T_{amb}=- 55(+5-0)^{o}C.

Characteristics	Symbols	MIL-STD-883 Test Method	Test Conditions Note 1	Limits		Units
				Min	Max	
Functional Test 1	-	3014	Verify Truth Table V_{IL}=0V,V_{IH}=3V V_{DD}=3V,V_{SS}=0V Note 2	-	-	-
Functional Test 2	-	3014	Verify Truth Table V_{IL}=0V,V_{IH}=15V V_{DD}=15V,V_{SS}=0V Note 2	-	-	-
Quiescent Current	I_{DD}	3005	V_{IL}=0V,V_{IH}=15V V_{DD}=15V,V_{SS}=0V Note 3 T_{amb}=+125^{o}C T_{amb}=- 55^{o}C	- -	1 0.1	µA

Characteristic	Input Conditions	Limit	Remark
	V_{IN}(A)	V_{OUT}(B)	
V_{IL2}	15V	≤ 0.1V ≤ 1V	T_{amb} = +22˚C, -55˚C T_{amb} = +125˚C Channel OFF
V_{IH1}	5V	≥ 4V	Channel ON
V_{IH2}	15V	≥ 12.5V	Channel ON

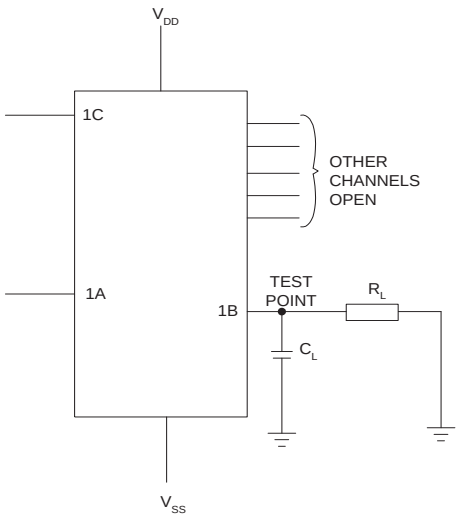
6. Input Clamp Voltage 2 to V_{DD}, V_{IC2}, shall be tested on each input as follows:



7. Guaranteed but not tested.
8. Read and record measurements shall be performed on a sample of 32 components with 0 failures permitted.
The pulse generator shall have the following characteristics:

V_{GEN} = 0 to V_{DD}; f = 500kHz; tr and t_f ≤15 ns (10% to 90%); duty cycle = 50%. Output load capacitance C_L = 50pF ±5% including scope probe, wiring and stray capacitance without component in the test fixture. Channel bias resistance R_L = as specified.

Propagation delay times shall be measured as follows:



VOLTAGE WAVEFORMS